

Search Notes

Application/Control No.

10/521,039

Examiner

Mark A. Williams

Applicant(s)/Patent under
Reexamination

HEELEY ET AL.

Art Unit

3676

SEARCHED

Class	Subclass	Date	Examiner
292	336.3	↓	
	336.5		
	338		
	359		mej

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR